(12)

EUROPEAN PATENT APPLICATION

(88) Date of publication A3: 31.12.2008 Bulletin 2009/01

(51) Int Cl.: **G06F 19/00** (2006.01)

- (43) Date of publication A2: 03.09,2008 Bulletin 2008/36
- (21) Application number: 08005920.7
- (22) Date of filing: 28.11.2000
- (84) Designated Contracting States: **DE FR GB IT**
- (30) Priority: 30.11.1999 JP 34108599
- (62) Document number(s) of the earlier application(s) in accordance with Art. 76 EPC: 00310545.9 / 1 107 159
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(54) Support method, quality control method, and device therefor

(57) The present invention quickly resolves troubles in an analysis device to perform effective external quality control. An analysis device (2) and a control device (1) are connected by a network (3). Error data and sample data taken from a measurement of a quality control substance are transmitted from the control device (1) to the analysis device (2). The analysis device (2) is made to be remotely operable from the control device (1) and when troubles arise repair from the control device (1) is possible. The control device (1) analyzes sample data, and provides the analysis results to a web page. The analysis device (2) accesses the web page using a WWW browser, and can perform external quality control in real time.

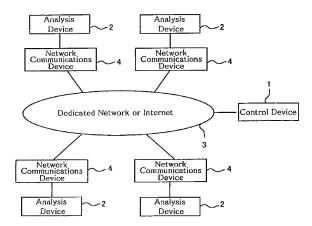


Fig.1



EUROPEAN SEARCH REPORT

Application Number

EP 08 00 5920

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ANNEX TO THE EUROPEAN SEARCH REPORT ON EUROPEAN PATENT APPLICATION NO.

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